NOTE
The Society is not responsible, as a body, for the statements and opinions advanced in this publication.
Foreword

The symposium on Progress in Quantitative Surface Analysis was held on 2–3 March 1977 in conjunction with the Pittsburgh Conference on Analytical Chemistry and Applied Spectroscopy in Cleveland, Ohio. The symposium was sponsored by the American Society for Testing and Materials through its Committee E-42 on Surface Analysis. N. S. McIntyre, Atomic Energy of Canada Limited and vice-chairman (publications) of ASTM Committee E-42, served as symposium chairman and editor of this publication. J. R. Cuthill, National Bureau of Standards and chairman of Committee E-42, David Hercules, University of Pittsburgh, and G. G. Sweeney, Westinghouse Research Laboratories, served as session chairmen. Papers from the symposium as well as appropriate papers from the regular Pittsburgh Conference sessions on surface analysis are included in this special technical publication.

Special thanks are due to the Pittsburgh Conference, Inc. and its 1977 program chairman J. E. Graham for their close cooperation with ASTM in arranging the connecting sessions and in contacting contributing authors. Acknowledgment is also made of the efforts of S. Bowman of ASTM in arranging the symposium. The editorial staff of ASTM is thanked for their assistance with the preparation of this book. The suggestions and assistance of Jane B. Wheeler, managing editor, during preparation are particularly noted and gratefully acknowledged.
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A Note of Appreciation to Reviewers

This publication is made possible by the authors and, also, the unheralded efforts of the reviewers. This body of technical experts whose dedication, sacrifice of time and effort, and collective wisdom in reviewing the papers must be acknowledged. The quality level of ASTM publications is a direct function of their respected opinions. On behalf of ASTM we acknowledge with appreciation their contribution.

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